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Roberts et al.

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(54) **SYSTEM AND METHOD TO FIX MIN-DELAY VIOLATION POST FABRICATION**

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See application file for complete search history.

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(57) **ABSTRACT**

A system and method of testing an integrated circuit provide a first clock signal to a first flip-flop with an output to a functional circuit, provide a second clock signal to a second flip-flop with an input from the functional circuit, wherein the second flip-flip has a minimum hold time, provide a test input to the first flip-flop, observe a signal propagation time through the functional circuit, determine the signal propagation time is less than the minimum hold time of the second flip-flop, and increasing a timing separation by adding a unit of delay to the first clock signal or subtracting a unit of delay from the second clock signal.

20 Claims, 7 Drawing Sheets